

**Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)**

Contribution ID : 1

Type : **not specified**

Overview of the ICTP and IAEA relevant activities

Monday, 26 September 2016 09:30 (0:30)

Content

Summary

Presenter(s) : SCANDOLO, Sandro (ICTP); SIMON, Aliz (IAEA)

Session Classification : DAY 1